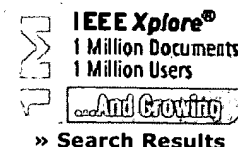


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Database Engineering and Applications Symposium, 2003. Proceedings. Seventh  
International, 16-18 July 2003  
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Greco, G.; Greco, S.; Zumpano, E.;  
Web Information Systems Engineering, 2002. WISE 2002. Proceedings of the Third  
International Conference on, 12-14 Dec. 2002  
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